	- <u>-</u> -		<del></del>	<del></del>	<del></del>			s	heet.	1 of 1
FORM PTO-1	1449	U.S. DEPARTMENT OF COMMERC						SERIAL NO.		
		PATENT AND TRADEMARK OFFICE		58268.00299			New Con. Appln.			
LIST	ΓOF!	REFERENCES	CITED BY APP	ED BY APPLICANT		APPLICANT COLORS				
		(Use several she		David WONG et al FILING DATE July 7, 2003			GROUP			
		(occount one					2663			
<del></del>			IIS PA	TENT DOCUMENT	's					
EXAMINER		DOCUMENT					SUB-	7	FILING	
INITIAL	<del> </del>	NO.	DATE	NAME	<u> </u>	CLASS	CLASS DATE			
<u> </u>	AA_	5,119,367	06/1992	Kawakatsu et al	awakatsu et al		232	<del> </del>		
	AB	5,680,396	10/1997	Morimoto et al	· · · · · · · · · · · · · · · · · · ·	370	392	↓		
	AC	6,081,511	06/2000	Carr et al		370	256	6		
	AD	6,108,306	08/2000	Kalkunte et al	<del></del>	370	235			
	AE	5,978,951	11/1999	Lawler et al.		370	392	2		
	AF	5,864,535	01/1999	Basilico		370	392	T		
	AG	5,461,615	10/1995	Henrion		370	392			
<u></u>	AH	5,271,003	12/1993	Lee et al.		370	392			
SH	AI	4,621,359	11/1986	McMillen	Millen		392	1		
			FOREIGN I	PATENT DOCUME	NTS					
		DOCUMENT NO. DATE COUNTRY		RY	CLASS CLA					
	LAJ									
	AK									
	AL							1		<del>                                     </del>
	<u> </u>	OTHER REI	EEDENCES (Includi	ing Author Title Da	to Portinant I	20000 5		J		
	1	OTHER REF	FERENCES (Includi	ng Aumor, Tille, Da	ile, Perunent i	ages, E	<i>G.)</i>			
Ам					•					
			*************							<del></del>
	AN									
,	AO									
		<u></u>								
EXAMINE	₹ /	Soon Hyun/	DATE CON	ISIDERED			-			
	,	my um/	•		3/2006					
*EXAMINE	R: Ir	nitial if reference consid	dered, whether or not cita	ition is in conformance v	vith MPEP 609; D	raw line thr	ough citatio	on if not	in	
	a	onformance and not co	onsidered. Include copy	of this form with next cor	mmunication to a	oplicant.				